



<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10777142</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>IDE ET AL.</p>
	<p>Examiner</p> <p>Al-Nazer, Leith A</p>	<p>Art Unit</p> <p>2821</p>


Class	SubClass	Date	Examiner
349	149-152	07/19/2006	Leith Al-Nazer
349	149-152	10/18/2006	Leith Al-Nazer

U.S. Patent and Trademark Office	Part of Paper No.: 20061018
----------------------------------	-----------------------------

<b>Interference Searched</b>  	Application/Control No.  10777142	Applicant(s)/Patent Under Reexamination  IDE ET AL.
	Examiner Al-Nazer, Leith A	Art Unit 2821

Class	SubClass	Date	Examiner
349	149-152	10/18/2006	Leith Al-Nazer

U.S. Patent and Trademark Office	Part of Paper No.: 20061018
----------------------------------	-----------------------------

<b>Search Notes</b>  	Application/Control No.  10777142	Applicant(s)/Patent Under Reexamination  IDE ET AL.
	Examiner Al-Nazer, Leith A	Art Unit 2821

Notes	Date	Examiner
Updated EAST prior art text search (see "Examiner Search Notes")	07/19/2006	Leith Al-Nazer
Updated EAST prior art text search (see "Examiner Search Notes")	10/18/2006	Leith Al-Nazer
EAST interference text search (see "Examiner Search Notes")	10/18/2006	Leith Al-Nazer
U.S. Patent and Trademark Office		Part of Paper No.: 20060719